

Notice of References Cited	Application/Control No. 10/567,602	Applicant(s)/Patent Under Reexamination NAKAGAWA ET AL.	
	Examiner TUAN A. PHAM	Art Unit 2618	Page 1 of 1

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*	B	US-2004/0113101	06-2004	Li et al.	250/492.22
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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